

Search Notes

Application/Control No.

10/730,567

Examiner

Patricia Leith

Applicant(s)/Patent under
Reexamination

FALLON, JOAN M.

Art Unit

1655

SEARCHED

Class	Subclass	Date	Examiner
none			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST: JPO,EPO,DERWENT,USPATFULL,U SPGPUBS,OCRBACKFILE	10/19/2005	PL
cont...	10/25/2005	pl
STN: Fil Reg & Indexed BIOSCIENCE database cluster (76 databases)	10/19/2005	PL
cont...	10/25/2005	PL
Inventor name search PALM/EAST	10/19/2005	PL

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